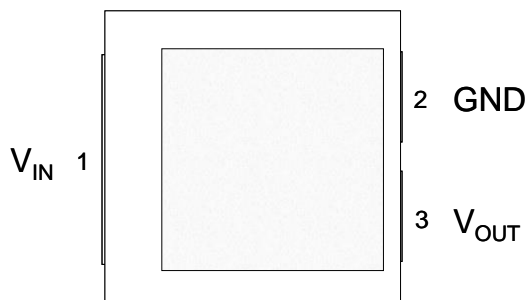
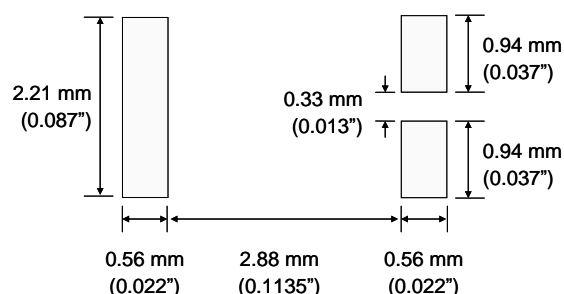


## CONFIGURATION INFORMATION

### Pin Configuration (Top View)



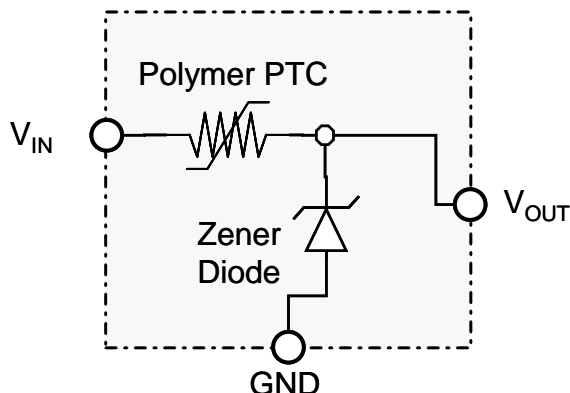
### Pad Dimensions



### PIN DESCRIPTION

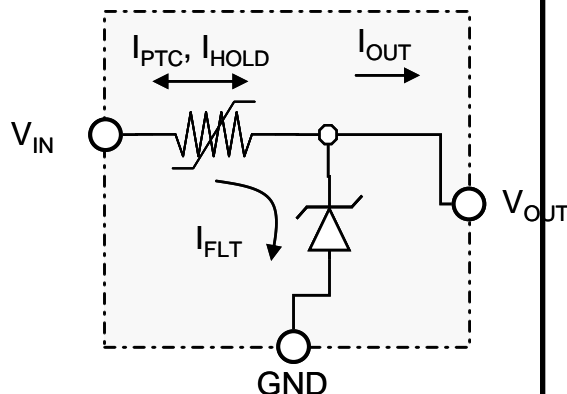
Pin Number	Pin Name	Pin Function
1	$V_{IN}$	$V_{IN}$ . Protected input to Zener diode.
2	GND	GND
3	$V_{OUT}$	$V_{OUT}$ . Zener regulated voltage output

## BLOCK DIAGRAM



## DEFINITION of TERMS

$I_{PTC}$	Current flowing through the PTC portion of the circuit
$I_{FLT}$	RMS fault current flowing through the diode
$I_{OUT}$	Current flowing out the $V_{OUT}$ pin of the device
Trip Event	A condition where the PTC transitions to a high resistance state, thereby significantly limiting $I_{PTC}$ and related currents.
Trip Endurance	Time the PTC portion of the device remains in a high resistance state.



## GENERAL SPECIFICATIONS

Operating Temperature -40° to +85°C

Storage Temperature -40° to +85°C

## ELECTRICAL CHARACTERISTICS<sup>1-3, 11</sup> (Typical unless otherwise specified)

$V_Z^4$ (V)			$I_{ZT}^4$ (A)	$I_{HOLD}^5$ (A) @ 20°C	Leakage Current		$R_{typ}^6$ (Ohms)	$R1_{Max}^7$ (Ohms)	$V_{INT} Max^8$		$I_{FLT} Max^9$		Tripped Power Dissipation <sup>10</sup>	
Min	Typ	Max			Test Voltage (V)	Max Current (mA)			$V_{INT} Max$ (V)	Test Current (A)	$I_{FLT} Max$ (A)	Test Voltage (V)	Power (W)	Test Voltage (V)
13.20	13.40	13.65	0.1	0.75	13.15	5.0	0.28	0.45	48	3	+2 -40	+48 -16	0.8	48

Note 1: Electrical characteristics determined at 25°C unless otherwise specified.

Note 2: This device is intended for limited fault protection. Repeated trip events or extended trip endurance can degrade the device and may affect performance to specifications. Performance impact will depend on multiple factors including, but not limited to, voltage, trip current, trip duration, trip cycles, and circuit design. For details or ratings specific to your application contact Littelfuse Circuit Protection directly.

Note 3: Specifications developed using 1.0 ounce 0.045" wide copper traces on dedicated FR4 test boards. Performance in your application may vary.

Note 4:  $I_{ZT}$  is the current at which  $V_Z$  is measured ( $V_Z = V_{OUT}$ ). Additional  $V_Z$  values are available on request.

Note 5:  $I_{HOLD}$ : Maximum steady state  $I_{PTC}$  (current entering or exiting the  $V_{IN}$  pin of the device) that will not generate a trip event at the specified temperature. Specification assumes  $I_{FLT}$  (current flowing through the Zener diode) is sufficiently low so as to prevent the diode from acting as a heat source. Testing is conducted with an "open" Zener.

Note 6:  $R_{Typ}$ : Resistance between  $V_{IN}$  and  $V_{OUT}$  pins during normal operation at room temperature.

Note 7:  $R1_{Max}$ : The maximum resistance between  $V_{IN}$  and  $V_{OUT}$  pins at room temperature, one hour after 1<sup>st</sup> trip or after reflow soldering.

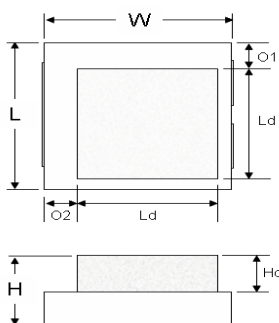
Note 8:  $V_{INT} Max$ :  $V_{INT} Max$  relates to the voltage across the PPTC portion of the PolyZen device ( $V_{IN}-V_{OUT}$ ).  $V_{INT} Max$  is defined as the voltage ( $V_{IN}-V_{OUT}$ ) at which typical qualification devices (98% devices, 95% confidence) survived at least 100 trip cycles and 24 hours' trip endurance at the specified voltage ( $V_{IN}-V_{OUT}$ ) and current ( $I_{PTC}$ ).  $V_{INT} Max$  testing is conducted using a "shorted" load ( $V_{OUT} = 0 V$ ).  $V_{INT} Max$  is a survivability rating, not a performance rating.

Note 9:  $I_{FLT} Max$ :  $I_{FLT} Max$  relates to the steady state current flowing through the diode portion of the PolyZen device in a fault condition, prior to a trip event.  $I_{FLT} Max$  is defined as the current at which typical qualification devices (12 parts per lot from 3 lots) survived 100 test cycles. RMS fault currents above  $I_{FLT} Max$  may permanently damage the diode portion of the PolyZen device. Testing is conducted with NO load connected to  $V_{OUT}$ , such that  $I_{OUT} = 0$ . "Test voltage" is defined as the voltage between  $V_{IN}$  to GND and includes the PolyZen Diode drop. Specification is dependent on the direction of current flow through the diode.  $I_{FLT} Max$  is a survivability rating, not a performance rating.

Note 10: The power dissipated by the device when in the "tripped" state, as measured on Littelfuse test boards (see note 3).

Note 11: Specifications based on limited qualification data and subject to change.

## MECHANICAL DIMENSIONS



		Min	Typical	Max
Length	L	3.85 mm (0.152")	4 mm (0.16")	4.15 mm (0.163")
Width	W	3.85 mm (0.152")	4 mm (0.16")	4.15 mm (0.163")
Height	H	1.4mm (0.055")	1.7 mm (0.067")	2.0 mm (0.081")
Length Diode	Ld	-	3.0 mm (0.118")	-
Height Diode	Hd	-	1.0 mm (0.039")	-
Offset	O1	-	0.6 mm (0.024")	-
Offset	O2	-	0.7 mm (0.028")	-

## SOLDER REFLOW RECOMMENDATIONS

### Classification Reflow Profiles

#### Profile Feature

Average Ramp-Up Rate (T<sub>smax</sub> to T<sub>p</sub>)

#### Pb-Free Assembly

3° C/second max.

#### Preheat

- Temperature Min (T<sub>smin</sub>)
- Temperature Max (T<sub>smax</sub>)
- Time (t<sub>smin</sub> to t<sub>smax</sub>)

150 °C

200 °C

60-180 seconds

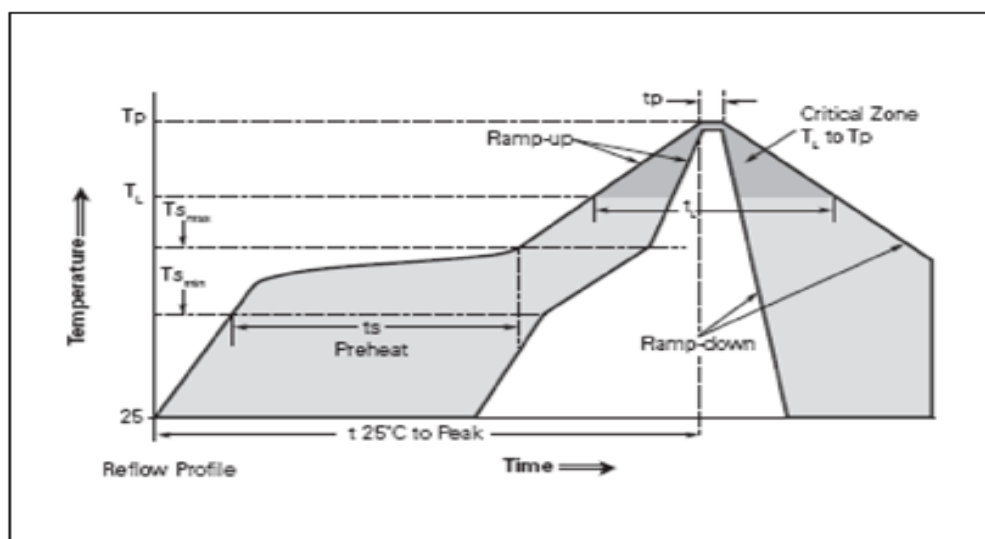
#### Time maintained above:

- Temperature (T<sub>L</sub>)

217 °C

- Time (t<sub>L</sub>)

60-150 seconds

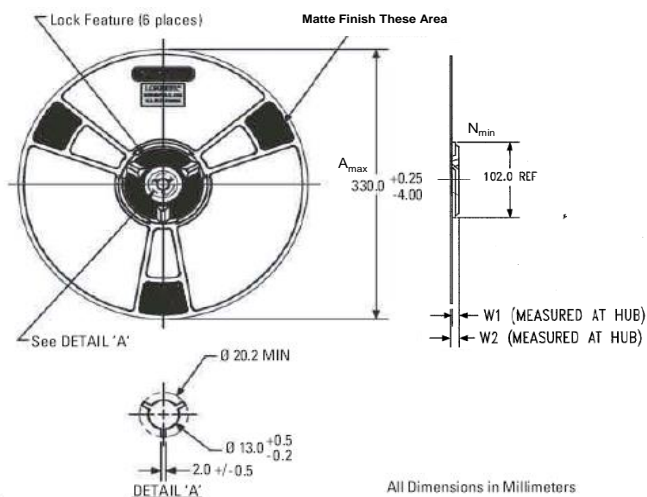


## PACKAGING

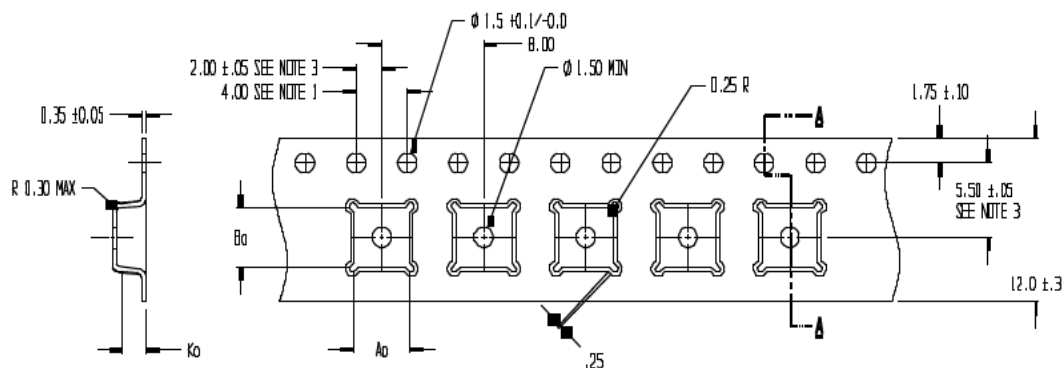
Packaging	Tape & Reel	Standard Box
ZENXXXVXXXAXXLS	3,000	15,000

## REEL DIMENSIONS

A<sub>max</sub> = 330  
N<sub>min</sub> = 102  
W<sub>1</sub> = 8.4  
W<sub>2</sub> = 11.1



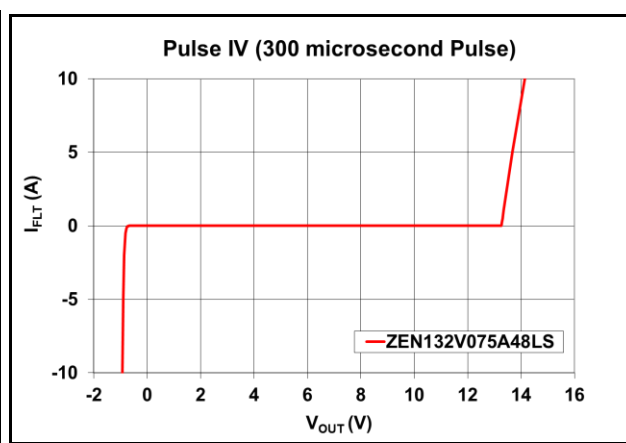
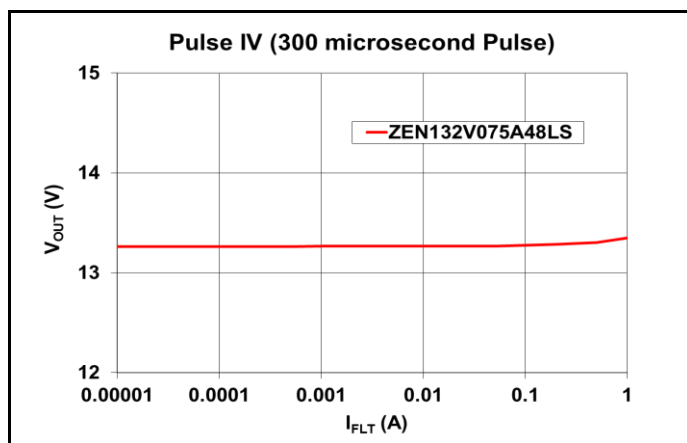
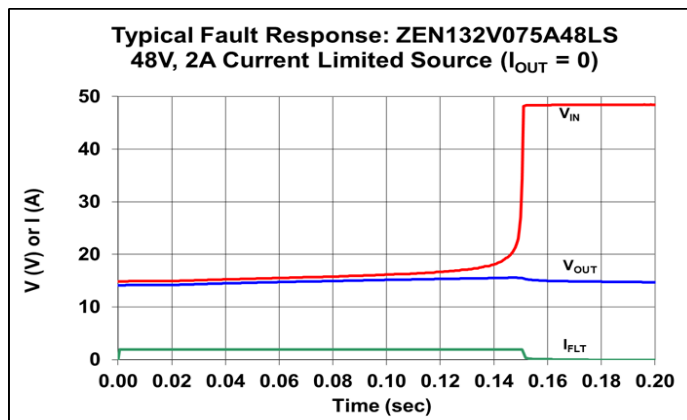
## TAPED COMPONENT DIMENSIONS

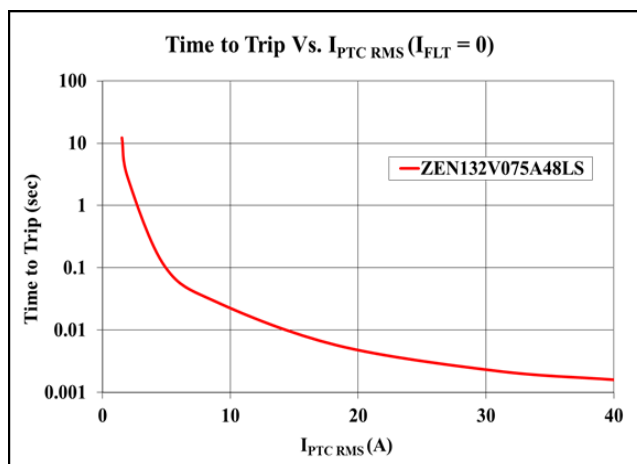
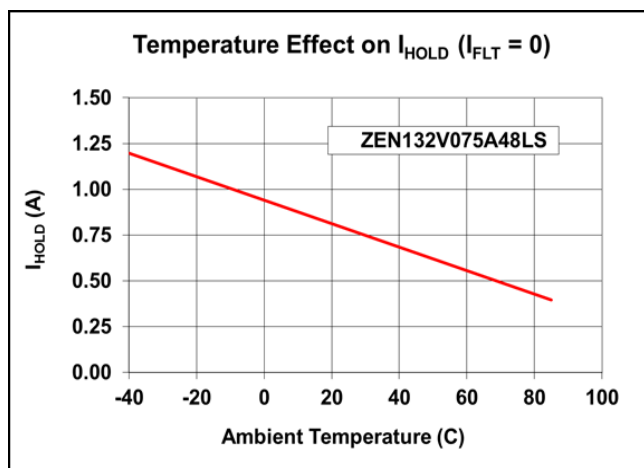
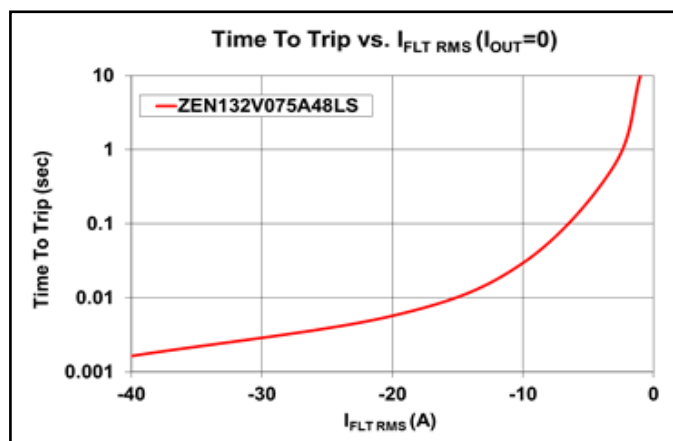
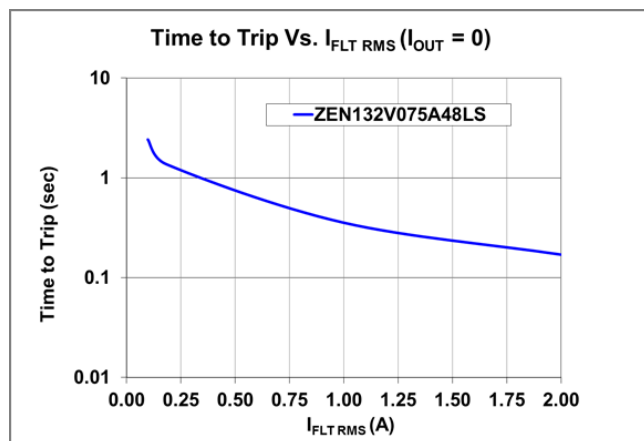
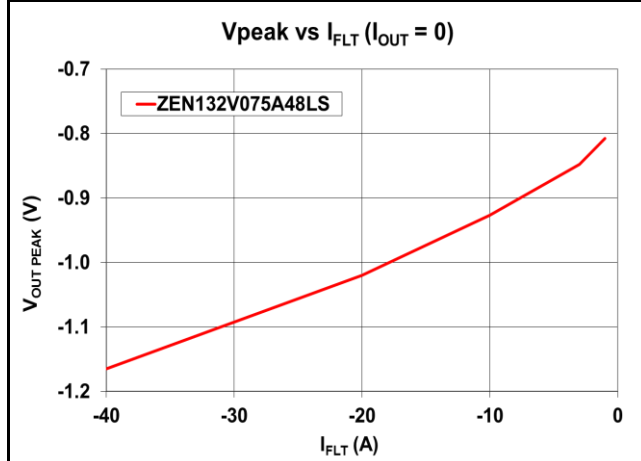
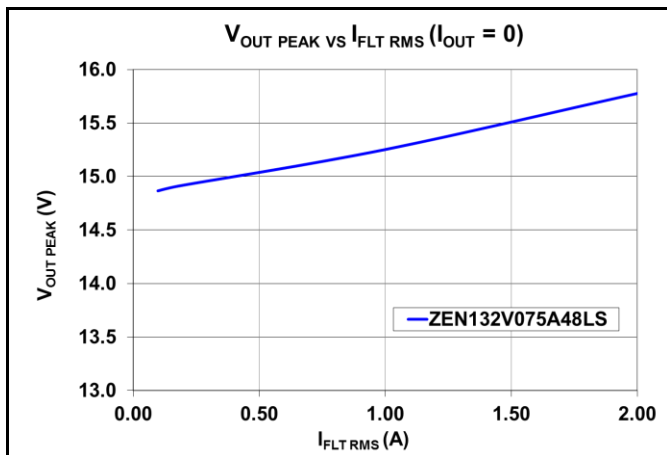


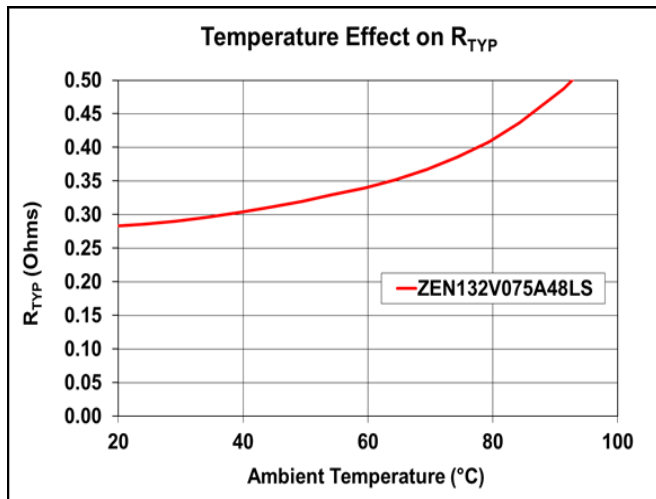
### NOTES:

1. 10 SPROCKET HOLE PITCH CUMULATIVE TOLERANCE ±0.2
  2. CAMBER IN COMPLIANCE WITH EIA 481
  3. POCKET POSITION RELATIVE TO SPROCKET HOLE MEASURED AS TRUE POSITION OF POCKET, NOT POCKET HOLE
- A<sub>a</sub> = 4.35  
B<sub>a</sub> = 4.35  
K<sub>a</sub> = 2.30

## TYPICAL CHARACTERISTICS







## MATERIALS INFORMATION

### ROHS Compliant

Directive 2002/95/EC  
Compliant

### ELV Compliant

Directive 2000/53/EC  
Compliant

### Halogen Free\*



\* Halogen Free refers to:  $Br \leq 900ppm$ ,  $Cl \leq 900ppm$ ,  $Br+Cl \leq 1500ppm$ .

## PolyZen

Polymer Enhanced Zener Diode  
Micro-Assemblies

**PRODUCT : ZEN132V075A48LS**

**DOCUMENT : SCD27364**  
**REV LETTER : D**  
**REV DATE: JULY 26, 2016**  
**PAGE NO.: 9 OF 8**

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